



Call for Papers

IEEE Open Journal of Instrumentation and Measurement (IEEE OJIM) Special Section on

Advances in Tomography for Industrial and Medical Applications

Tomography techniques have been developed for many years and have found many applications. Because of the advance in hardware devices, computation power and new concepts such as big data and Artificial Intelligence (AI) including machine learning and its subset of deep learning, researchers are continuing to make progress in tomography.

This special section focuses on recent development in tomography techniques for both industrial and medical applications. The topics for this special section include but are not limited to the following:

- Optimization of sensor design
- Hardware design with new integrated circuits, such as capacitance-to-digital converter (CDC)
- New image reconstruction algorithms, in particular iterative algorithms
- Post data processing and image processing
- Big data processing for key parameter extraction
- Deep learning and machine learning for image reconstruction
- Implementation of AI-based tomography measurements
- Evaluation of hardware performance
- Evaluation of image quality
- Comparison between different modalities
- Electrical tomography for clinic trial

Each accepted paper for this Special Section will receive an Open Access fee waiver; i.e., accepted papers won't be charged Open Access fee.

Deadlines

Submission: June 1, 2022
First decision: June 25, 2022
Final decision: August 5, 2022
Publication Volume: 2022

For more info and submission instructions, please visit OJIM's official website: <http://ojim.ieee-ims.org/>

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